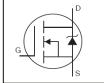
HEXFET® Power MOSFET



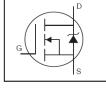
- Logic -Level Gate Drive
- Advanced Process Technology
- Isolated Package
- High Voltage Isolation = 2.5KVRMS (5)
- Sink to Lead Creepage Dist. = 4.8mm
- Fully Avalanche Rated
- Lead-Free

Description

of applications.



$V_{ exttt{DSS}}$	100V
R _{DS(on)}	0.10Ω
l _n	12A



	•
TO-220 Full-Pak	
S	

G	D	S
Gate	Drain	Source

The TO-220 Fullpak eliminates the need for additional insulating
hardware in commercial-industrial applications. The moulding
compound used provides a high isolation capability and a low
thermal resistance between the tab and external heatsink. This
isolation is equivalent to using a 100 micron mica barrier with
standard TO-220 product. The Fullpak is mounted to a heatsink
using a single clip or by a single screw fixing.
thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low onresistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety

Page Dout Number	Dookogo Typo	Standard Pack		Orderable Bort Number	
Base Part Number	Package Type	Form	Quantity	Orderable Part Number	
IRLI530NPbF	TO-220 Full-Pak	Tube	50	IRLI530NPbF	

Absolute Maximum Ratings					
Symbol	Parameter	Max.	Units		
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	12			
_D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	8.6	Α		
DM	Pulsed Drain Current ①⑥	60			
P _D @T _C = 25°C	Maximum Power Dissipation	41	W		
	Linear Derating Factor	0.27	W/°C		
V_{GS}	Gate-to-Source Voltage	± 16	V		
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②⑥	150	mJ		
AR	Avalanche Current ①⑥	9.0	А		
= AR	Repetitive Avalanche Energy ①	4.1	mJ		
dv/dt	Peak Diode Recovery dv/dt36	5.0	V/ns		
Γ _J	Operating Junction and	-55 to + 175			
T _{STG} Storage Temperature Range			°C		
	Soldering Temperature, for 10 seconds (1.6mm from case)	300			
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)			

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case		3.7	°C/W
$R_{ heta JA}$	Junction-to-Ambient		65	C/VV

2017-04-27



Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.122		V/°C	Reference to 25°C, I _D = 1mA 6
				0.100		$V_{GS} = 10V, I_D = 9.0A$
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.120	Ω	$V_{GS} = 5.0V, I_D = 9.0A$
,				0.150		V _{GS} = 4.0V, I _D = 8.0A
$V_{GS(th)}$	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Trans conductance	7.7				V _{DS} = 50V, I _D = 9.0A [©]
1	Drain-to-Source Leakage Current			25	μA	V _{DS} = 100V, V _{GS} = 0V
I _{DSS}	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 16V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	IIA	$V_{GS} = -16V$
Q_g	Total Gate Charge			34		$I_{D} = 9.0A$
Q_{gs}	Gate-to-Source Charge			4.8	nC	$V_{DS} = 80V$
Q_{gd}	Gate-to-Drain Charge			20		V _{GS} = 5.0V , See Fig. 6 and 13④⑥
t _{d(on)}	Turn-On Delay Time		7.2			$V_{DD} = 50V$
t _r	Rise Time		53			$I_{D} = 9.0A$
t _{d(off)}	Turn-Off Delay Time		30		ns	$R_G = 6.0\Omega, V_{GS} = 5.0V$
t _f	Fall Time		26			R _D = 5.5Ω, See Fig. 10⊕⊚
L_D	Internal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
Ls	Internal Source Inductance		7.5		ПП	from package and center of die contact
C _{iss}	Input Capacitance		800			$V_{GS} = 0V$
C _{oss}	Output Capacitance		160		pF	V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		90		þΓ	f = 1.0MHz, See Fig. 5®
С	Drain to Sink Capacitance		12			f = 1.0MHz

Source-Drain Ratings and Characteristics

000.00 B	Source Stain Natings and enalactoristics					
	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			12		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ① ⑤			60	A	integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 6.6A, V_{GS} = 0V $ ④
t _{rr}	Reverse Recovery Time		140	210	ns	$T_J = 25^{\circ}C$, $I_F = 9.0A$
Q _{rr}	Reverse Recovery Charge		740	1100	nC	di/dt = 100A/µs ④⑥
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25$ °C, L = 3.1mH, $R_G = 25\Omega$, $I_{AS} = 9.0A$ (See fig. 12)
- $\label{eq:local_state} \mbox{ } \mbo$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- ⑤ t=60s, *f*=60Hz
- © Uses IRL530N data and test conditions.



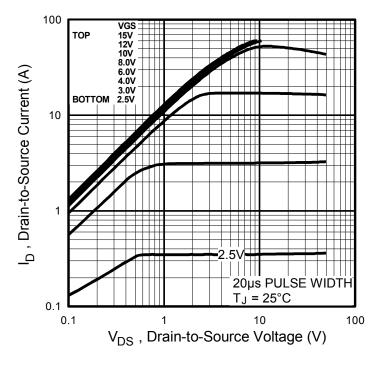


Fig. 1 Typical Output Characteristics

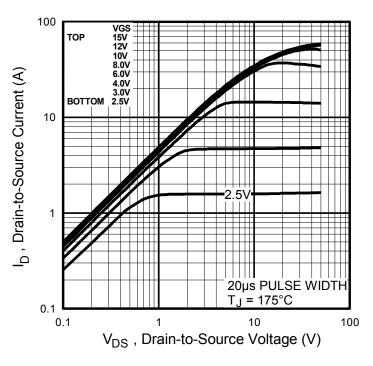


Fig. 2 Typical Output Characteristics

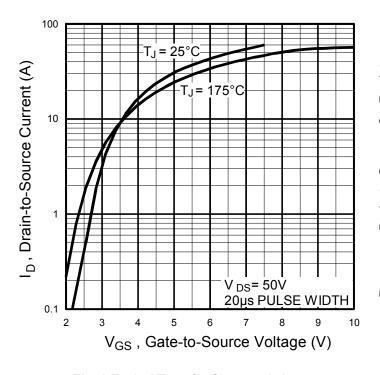


Fig. 3 Typical Transfer Characteristics

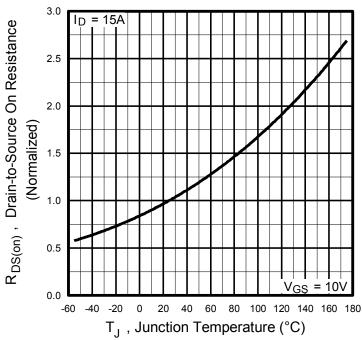


Fig. 4 Normalized On-Resistance vs. Temperature



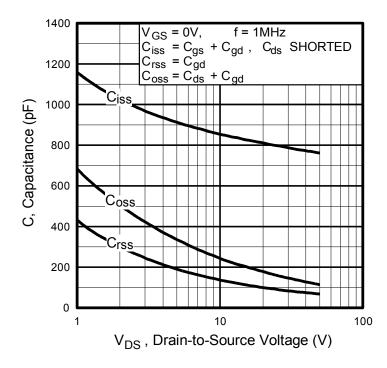


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

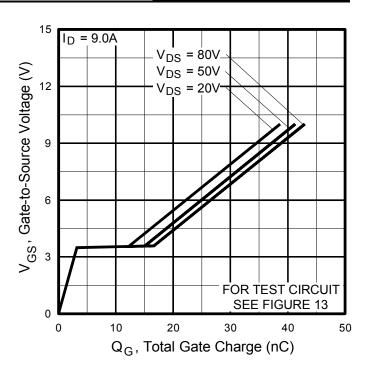


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

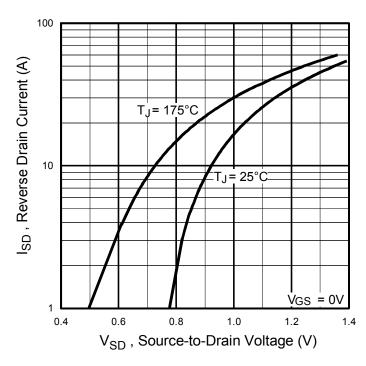


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

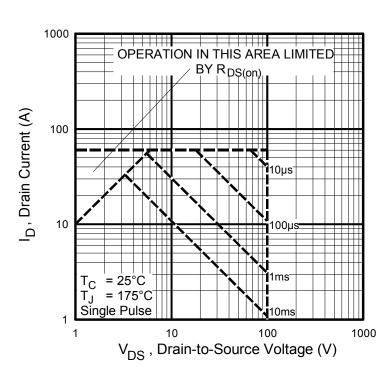


Fig 8. Maximum Safe Operating Area



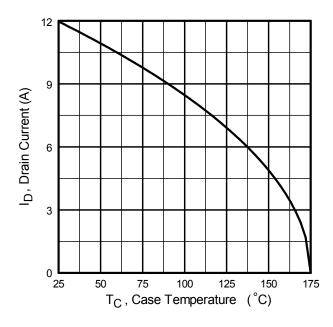


Fig 9. Maximum Drain Current vs. Case Temperature

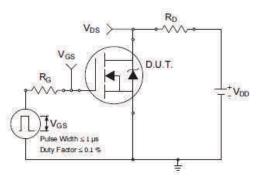


Fig 10a. Switching Time Test Circuit

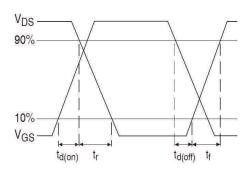


Fig 10b. Switching Time Waveforms

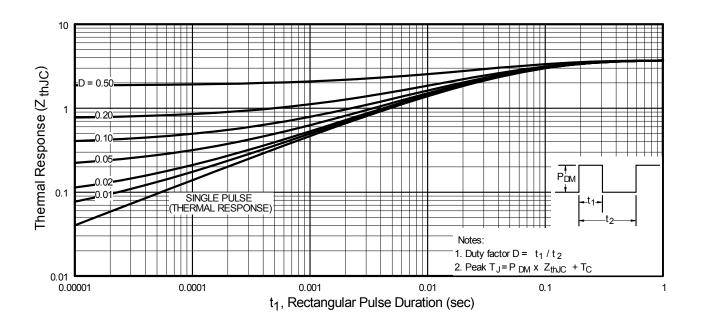


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



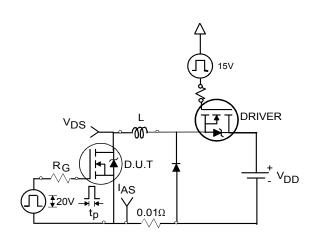


Fig 12a. Unclamped Inductive Test Circuit

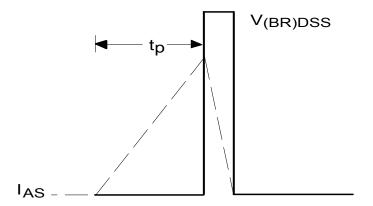


Fig 12b. Unclamped Inductive Waveforms

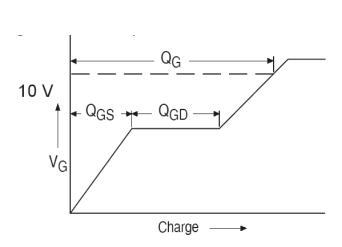


Fig 13a. Gate Charge Waveform

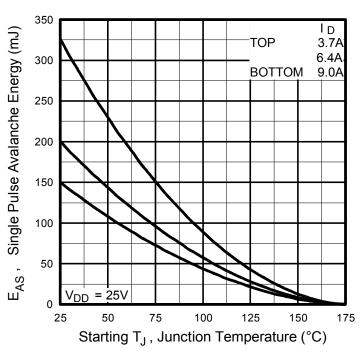


Fig 12c. Maximum Avalanche Energy vs. Drain Current

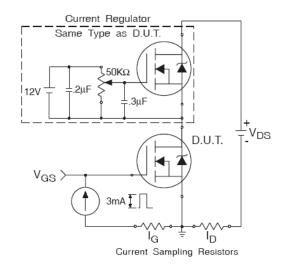
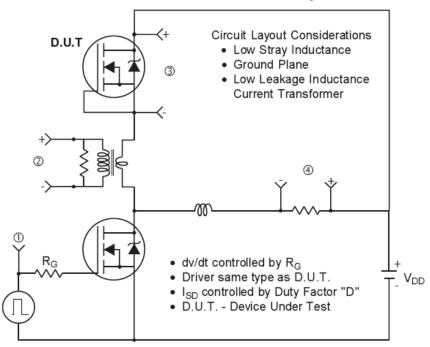


Fig 13b. Gate Charge Test Circuit

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Peak Diode Recovery dv/dt Test Circuit



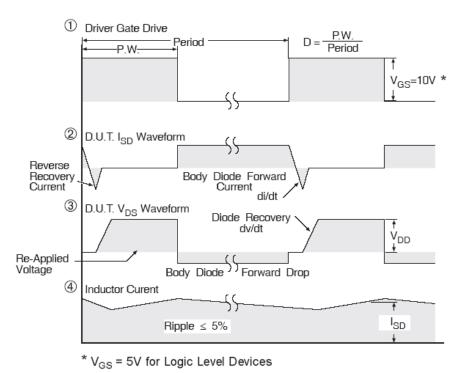
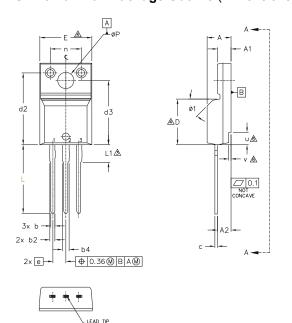
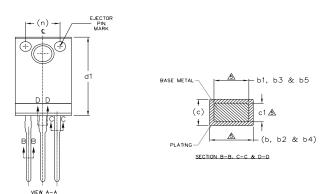


Fig 14. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs



TO-220 Full-Pak Package Outline (Dimensions are shown in millimeters (inches))





NOTES:

1.0 DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.

2,0 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3,改 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

DIMENSION D & E DO NOT INCLUDE MOLD FLASH, MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTER MOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63, 65 & c1 APPLY TO BASE METAL ONLY.

6.0 step optional on plastic body defined by dimensions u & v.

7.0 CONTROLLING DIMENSION: INCHES.

S Y M	DIMENSIONS				
B	MILLIM	ETERS	INC	HES	0 T E S
L	MIN.	MAX.	MIN.	MAX.	S
А	4.57	4.83	.180	.190	
A1	2.57	2.82	.101	.111	
A2	2.51	2.92	.099	.115	
ь	0.61	0.94	.024	.037	
ь1	0.61	0.89	.024	.035	5
b2	0.76	1.27	.030	.050	
ь3	0.76	1.22	.030	.048	5
b4	1.02	1.52	.040	.060	
b5	1.02	1.47	.040	.058	5
С	0.33	0.63	.013	.025	
c1	0.33	0.58	.013	.023	5
D	8.66	9.80	.341	.386	4
d1	15.80	16.13	.622	.635	
d2	13.97	14.22	.550	.560	
d3	12.29	12.93	.484	.509	
E	9.63	10.74	.379	.423	4
е	2.54	BSC	.100	BSC	
L	13.21	13.72	.520	.540	
L1	3.10	3.68	.122	.145	3
n	6.05	6.60	.238	.260	
ØΡ	3.05	3.45	.120	.136	
u	2.39	2.49	.094	.098	6
V	0.41	0.51	.016	.020	6
Ø1	_	45°	_	45°	

LEAD ASSIGNMENTS

<u>HEXFET</u>

1.- GATE

2.- DRAIN

3.- SOURCE

IGBTs, CoPACK

1.- GATE

2.- COLLECTOR

3.- EMITTER

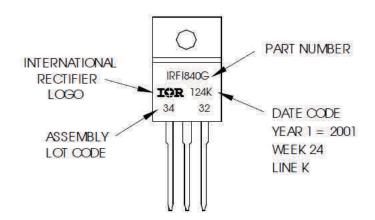
TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFI840G WITH ASSEMBLY

LOT CODE 3432

ASSEMBLED ON WW 24, 2001 IN THE ASSEMBLY LINE "K"

Note: "P" in assembly line position indicates "Lead-Free"



TO-220AB Full-Pak packages are not recommended for Surface Mount Application.

Note: For the most current drawing please refer to website at http://www.irf.com/package/

2017-04-27



Qualification Information

Qualification Level	Industrial (per JEDEC JESD47F) [†]			
Moisture Sensitivity Level	TO-220 Full-Pak N/A			
RoHS Compliant	Yes			

† Applicable version of JEDEC standard at the time of product release.

Revision History

Date	Comments	
04/27/2017	 Changed datasheet with Infineon logo - all pages. Corrected Package Outline on page 8. 	
04/21/2017	Added disclaimer on last page.	

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Edition 2016-04-19 Published by Infineon Technologies AG 81726 Munich, Germany

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